REVISIONS								
ZONE	REV.	DESCRIPTION DATE APPRO						
		Original Release- Preliminary	02/22/08	DWB				

REV STATUS	REV	-	-	-	-	-	-	-	-	-	-	-	_	_	-	-	-
SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
REV STATUS	REV																
SHEETS	SHEET	17	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
Planar Monolithics Industrian 7311-G Grove Road, Frederick, M									,								
CHECK							(SCRE	ENIN	NG TI	EST I	PROG	CEDU	JRE			
APPD. ENGR. PROD.					MODEL: RFFD-618-730049 PART No. T0737SOCN730049-001 RF, FILTER DETECTOR ASSEMBLY												
QC.																	
				S	SIZE:	A		FS	CM: 0Z)	KZ8	D	RAWIN	G No 18	30-R000	0-000		
				F	REV:	-		SC	ALE: N	I/A	S	HEET_	_1_	_ OF _	6	_	

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PMI

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SCREENING

TEST PROCEDURE (SCTP)

FOR

PMI MODEL NUMBER: RFDD-618-730049

HERMETICALLY SEALED RF, FILTER DETECTOR ASSEMBLY

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1.0 SCOPE

The purpose of this document is to provide a description of the Qualification Tests to be performed on PMI Model RFFD-618-730049 the hermetically sealed RF, Filter Detector Assembly. These tests are designed to meet the Screening Test requirements outlined in the Microwave Electronic Systems Source Control Drawing 730049 Rev. 1.

2.0 SCREENING TESTS

All units will initially be screened in accordance with the table shown below:

TABLE OF SCREENING TESTS

TABLE I

Item Number	SCD PARA.	TEST	WHERE PERFORMED	HOW DOCUMENTED		
1.	4.4	Internal Visual	PMI QA	Traveler Sign-Off		
2	4.5.4	Hermetic Seal	Litron, MA	Litron Test Data and C of C		
3	4.5.7	Fine and Gross Leak Tests	Litron, MA	Litron Test Data and C of C		
4	4.5 (Implied)	Electrical "Flash" Test	PMI	Traveler Sign-Off		
5	4.5.3.A.1	Stabilization Bake	PMI	Chart Record		
6	4.5 (Implied)	Electrical "Flash" Test	PMI	Traveler Sign-Off		
7	4.5.3.A.2	Thermal Shock	PMI	Chart Record		
8	4.5 (Implied)	Electrical "Flash" Test	PMI	Traveler Sign-Off		
9	4.5.3.A.3	Mechanical Shock	Mechanical Shock Qual-Test, Florida Qual			
10	4.5.3.A.4	Vibration	Qual-Test, Florida	Qual-Test Report		
11	4.5 (Implied)	Initial Electrical Testing	PMI Test Lab	Test Data Sheet		
12	4.5.3.B	Temperature Cycling	PMI	Chart Record		
13	4.5.5	Final Electrical Testing	PMI Test Lab	Test Data Sheet		

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3.0 SCREENING TEST METHODS

SCREENING TEST METHODS TABLE II

ITEM	SCD PARA.	TEST	METHOD				
1	4.4	Internal Visual	MIL-STD-883, Method 2017				
2	4.5.4	Hermetic Seal	MIL-STD-202, Method 112				
3	4.5.7	Fine and Gross Leak Tests	MIL-STD-202, Method 112, Condition C				
4	4.5 (Implied)	Electrical "Flash" Test	Network Analyzer sweep to assure operation.				
5	4.5.3.A.1	Stabilization Bake	MIL-STD-883, Method 1008, Condition C (125°C/168 hrs)				
6	4.5 (Implied)	Electrical "Flash" Test	Network Analyzer sweep to assure operation.				
7	4.5.3.A.2	Thermal Shock	MIL-STD-202, Method 107, Test Condition B-1 (25 cycles -65°C to +125°C)				
8	4.5 (Implied)	Electrical "Flash" Test	Network Analyzer sweep to assure operation.				
9	4.5.3.A.3	Mechanical Shock	MIL-STD-883, Method 2002, Condition B, Y1 axis only.				
10	4.5.3.A.4	Random Vibration	MIL-STD-883, Method 2026, Table 1, Test Condition E, 10 minutes. One axis perpendicular to mounting plane.				
11	4.5 (Implied)	Electrical "Flash" Test	Network Analyzer sweep to assure operation.				
12	4.5.3.B	Temperature Cycling	24 cycles; 30 min @ -54°C, 2.5 hrs @ +95°C. Transition time not to exceed 30 minutes. Max. D.C. supply voltage and logic signals applied during the transition to and "hot" part of cycle. Power off during the transition to and "cold" part of cycle.				
13	4.5.5	Final Electrical Testing	Per PMI ATP				

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- Refer to ¶ 3.4 of and Figure 1 of ATP, Drawing 140-R000-000 for process and block diagram for performing "flash" tests. Figure 1 of ATP is attached on page 7 of this procedure.
- 3.2 Initial and Final Electrical Testing will be performed as indicated in the ATP.

4.0 SCREENING TEST OUTPUT

- 4.1 If the unit fails to pass any Screening Test, it must be repaired and the re-screening tests performed as follows:
 - A. If failure occurs during Thermal Shock Repeat all tests except Stabilization Bake.
 - B. If failure occurs during Mechanical Shock or Random Vibration Repeat all tests except Stabilization Bake and conduct 10 Thermal Shock cycles.
 - C. If failure occurs during Temperature Cycling Repeat a minimum of 10 Thermal Shock cycles, the Random Vibration Test and continue Temperature Cycling at the point of failure or for three consecutive failure free cycles, whichever is greater.
 - D. If any electrical component is replaced, stabilization bake must be repeated.
 - E. A Screening Test Report will be prepared including all documentation listed in Table I of this procedure.
 - F. If the repair requires that active devices be replaced with a non-screened replacement, the entire temperature cycling burn-in shall be repeated.

ATP FIGURE 1

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